

N85-32418

PHYSICS OF HEAVILY DOPED SILICON AND
SOLAR-CELL PARAMETER MEASUREMENT

UNIVERSITY OF FLORIDA

Fred A. Lindholm

CONTRACT: PHYSICS OF HEAVILY
DOPED SILICON AND SOLAR-CELL
PARAMETER MEASUREMENTCONTRACTOR: UNIVERSITY OF
FLORIDA, FRED A. LINDHOLMGOALS: THEORY & EXPERIMENT ON
 ΔE_G ENERGY GAP, τ LIFETIME, S RECOMBINATION
 D VELOCITY, DIFFUSIVITY, MOBILITY
IF N AND/OR P IS HIGH.

ALSO

ACCURATE DETERMINATION OF $\tau, S,$
IN QUASINEUTRAL REGIONS

REPORT DATE: 10/2/84 (3 MOS.)

*Colored & Presented by
C. Tang Sah*

HIGH-EFFICIENCY SILICON SOLAR CELL RESEARCH

Status (Briefly)

3 Parameters: ΔE_G , τ_B , S_{BSF}

1

1. ENERGY-GAP MODEL DEVELOPED,
COMPARED WITH ΔE_G
PHOTOLUMINESCENT
AND TRANSPORT DATA.

2

2. ELECTRICAL SHORT-CIRCUIT
CURRENT DECAY (ESSCD) τ_B, S_{BSF}
DEVELOPED AND IMPROVED

3. ESSCD AUGMENTED BY ADMITTANCE
VS. ω AND V (FORWARD)

4. ESSCD+ADMITTANCE APPLIED TO
MEASURE S AND τ FOR BASE OF
MANY BSF SOLAR CELLS

Publications

2 [ESSCD IN TRANS ED, Y · ESSCD
BEING WRITTEN, τ_B, S_{BSF}

1 [ENERGY GAP MODEL IN ΔE_G
PHOTOVOLTAICS CONF.,
ALSO DETAILED VERSION UNDER
REVIEW, PHYS. REV.

CO-WORKERS: A. NEUGROSCHER, ALL
WORK: P.T. LANDSBERG, C.T. SAH,
AND NEUGROSCHER ON ENERGY GAP.

HIGH-EFFICIENCY SILICON SOLAR CELL RESEARCH

Remarks on Energy Gap Model

● ENERGY GAP = KEY PARAMETER

● SIMPLE USEFUL FORMULA

● REPRESENTS EXPERIMENTAL FACTS

5K (OPTICAL = PL)

300K (TRANSPORT DATA)

● HEAVILY DOPED (LARGE N OR P)

● HIGHLY EXCITED (LARGE N AND P)

STRONG IRRADIATION

P/N TRANSITION REGION

● T DEPENDENCE

SOLAR CELLS AT 300K

EXPERIMENTS, OTHER T

- ~~Handwritten scribbles~~
- Simple understandable Theory :-
 - Debye (Carrier) Screening ← Electrostatic Coulombic
 - SAH (1966), chapter 6
 - SAH, McNutt, Chan, TR28 (June 1974)
 - SAH, et al, SOLAR CELL (1978)
 - LANDSBERG, N.L.S. (1984)

HIGH-EFFICIENCY SILICON SOLAR CELL RESEARCH

TEMPERATURE DEPENDENCES OF

$\sqrt{n_i p_i}/n_i$, E_G , n_i and L_D
OF SILICON

C. T. Sah, N. J. McMurtt and C. H. Chan

Technical Report No. 28

June 27, 1974

Solid State Electronics Laboratory

Technical Report No. 28

June 27, 1974

Electrical Engineering Research Laboratories

University of Illinois

Urbana, Illinois

The actual energy gap also includes the electron-hole, electron-electron and hole-hole electrostatic interaction energies which reduces the energy gap at high carrier concentrations. This effect is represented by ΔE_G ,

$$\Delta E_G = -e/4\pi\epsilon_0(\lambda_D+a) \quad (4)$$

$$= -1.23 \times 10^{-4} / (L_D+a) \text{ Volts} \quad (5)$$

HIGH-EFFICIENCY SILICON SOLAR CELL RESEARCH

1984 Landsberg Version

EXPRESSION FOR GAP SHRINKAGE

$$(1): E_G(N, P) = W + \frac{e^2}{\epsilon a} e^{-k_D(N, P) a}$$

$$(2): E_G = W + \frac{e^2}{\epsilon a}, \text{ for } N = P = 0$$

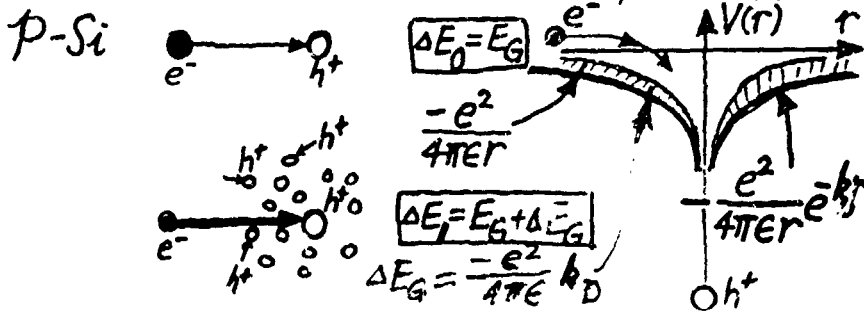
$$(3): \Delta E_G = \frac{e^2}{\epsilon a} [1 - e^{-k_D(N, P) a}]$$

$$= \frac{e^2}{\epsilon} k_D(N, P)$$

$$\lambda_D = \frac{1}{k_D} = \text{Debye Screening Length}$$

1966 Sah Version: Screening by Majority

★ carriers on minority carrier ΔE_G
 NOTE: ΔE_G data is from minority carrier experiments!



Screening Wave Number k_D

$$k_D^2 = \frac{4\pi e^2}{\epsilon_0 \epsilon_r} \left[\frac{N_D}{C} F_{-1/2}(\eta_D) + \frac{N_A}{C} F_{-1/2}(\eta_A) + \dots \right]$$

FOR GENERAL N AND P.

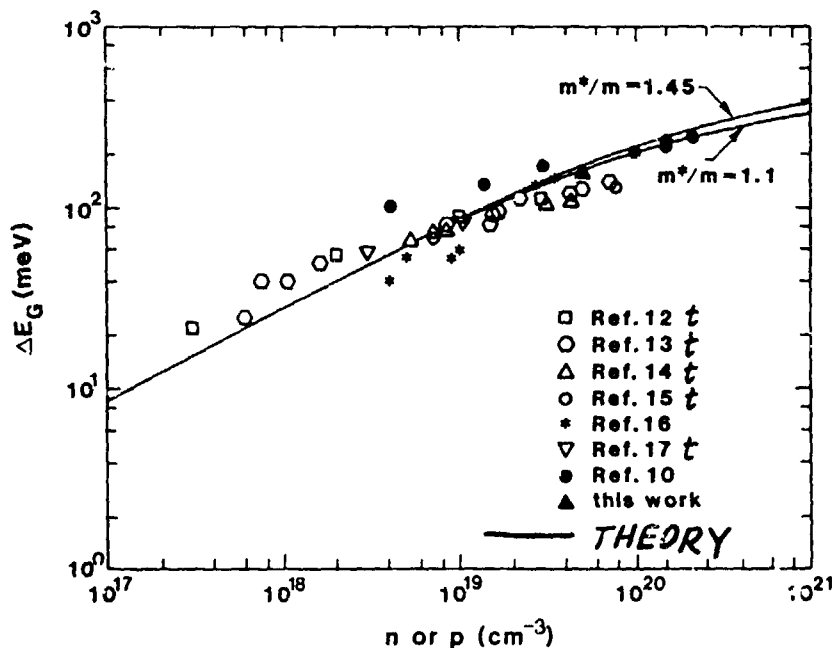
FOR LOW CONCENTRATIONS, FERMI INTEGRALS BECOME EXPONENTIALS:

$$k_D^2 = \frac{4\pi e^2}{\epsilon_0 \epsilon_r} (N + P) / kT$$

OR, FOR DEGENERATE DENSITY N,

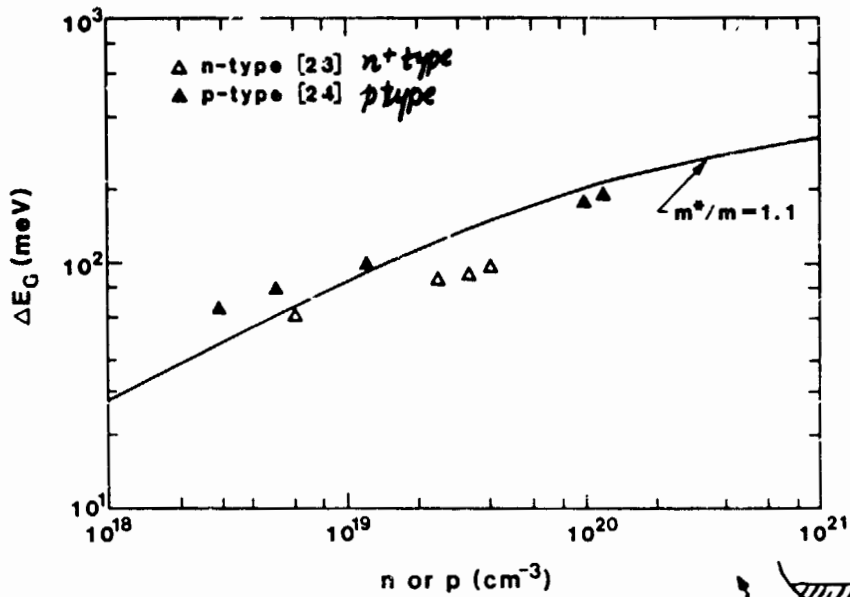
$$k_D^2 = \left(\frac{3}{\pi} \right)^{1/3} \left(\frac{2 m^*}{\hbar^2} \right)^{2/3} \left(\frac{2}{\pi} \right)^{1/3} N^{1/3}$$

MKS unit
(4π of CGS taken out.)

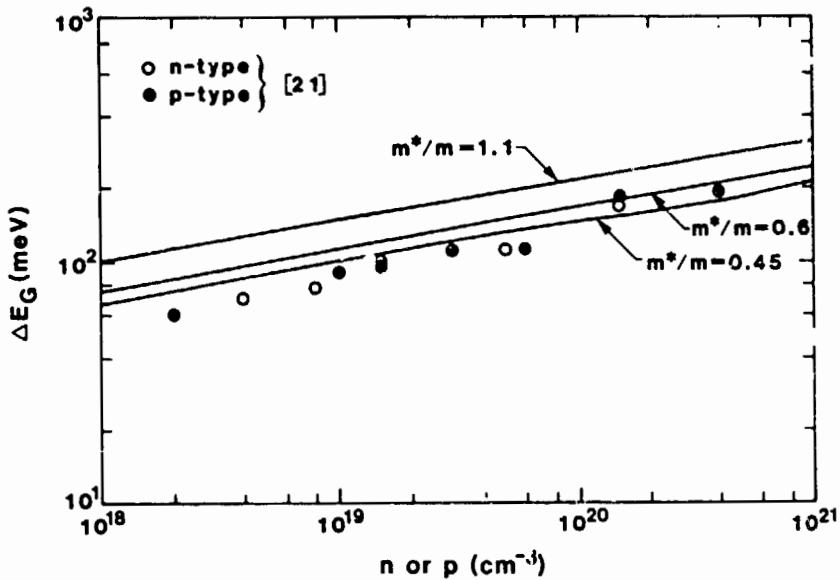
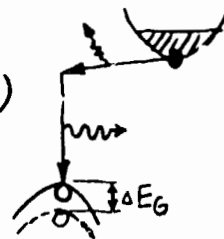


Comparison with minority carrier transport or 'pn' product measurements in bipolar devices: diodes, transistors.

HIGH-EFFICIENCY SILICON SOLAR CELL RESEARCH



Luminescence data (Dumke)
 at 300K
 23. Dumke, APL 42, 196 (1983)
 24. Dumke, JAP 54, 3200 (1983)



5K photoluminescence and excitation data
 Wagner PR B29, 2002 (1984)

HIGH-EFFICIENCY SILICON SOLAR CELL RESEARCH

2. MEASUREMENT OF S_{BSF} AND τ_B IN QUASINEUTRAL BASE OF BSF CELLS

ESSCD \leftrightarrow slope & intercept

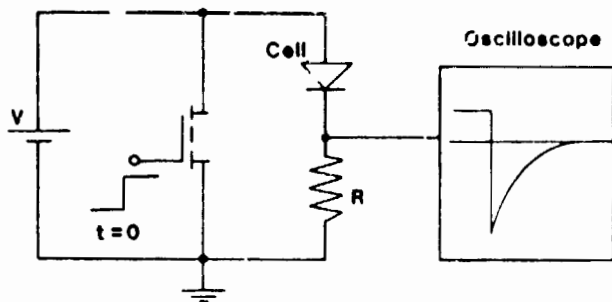
1. REPORT IMPROVED ESSCD: ELECTRICAL SHORT-CIRCUIT CURRENT DECAY BY USE OF FAST MOS TRANSISTOR SWITCH (10 ns.).
2. ADVANTAGE OF ESSCD VS OPEN-CIRCUIT VOLTAGE DECAY, REVERSE STEP RECOVERY, ETC. IT AVOIDS INFLUENCE OF HOLES & ELECTRONS IN P/N SCR BY FORCING DENSITIES TO EQUILIBRIUM VALUES IN 10 ps.
3. TO MEASURE S AND τ IN BASE YOU NEED SLOPE OF $\log v(t)$ AND ONE OTHER PIECE OF DATA. THIS IS BEST PROVIDED BY $Y(j\omega, V) =$ ADMITTANCE MEASURED ON BRIDGE. Y PROVIDES TWO THINGS:
- (A) SEPARATION OF Q_{NB} FROM Q_{NB} BY CHANGING ω .
 - (B) CONFINEMENT OF Y RESPONSE TO VOLUME (NOT SURFACE) FOR LARGE ω ; THUS CAN GET τ EVEN IF $DIFF. LENGTH > BASE THICKNESS$.

ESSCD
 $G_{QN} \text{ VS } \omega$
 $C_{HF} - C_{LF} \rightarrow \tau_B$

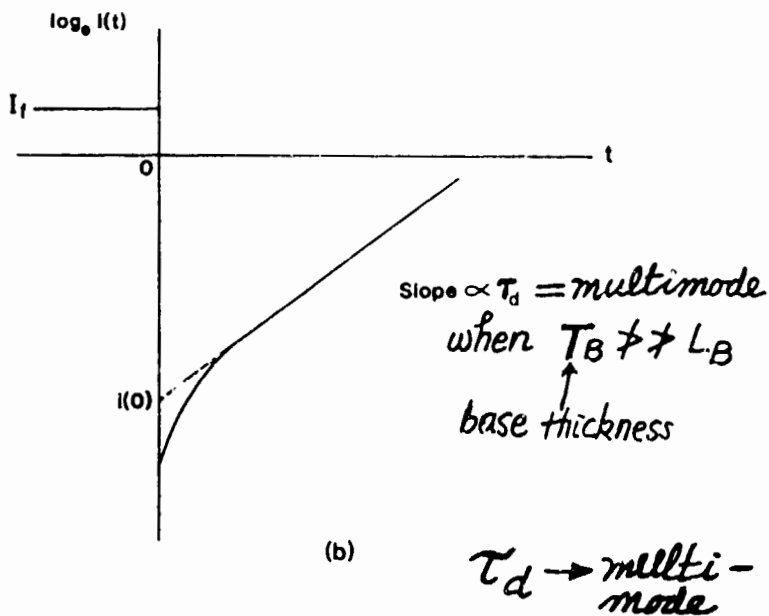
$Y(\omega)$ actually - $C_{HF} + C_{LF} = G_{QN} \text{ VS } \omega$

$G_{QN} \text{ VS } \omega$

HIGH-EFFICIENCY SILICON SOLAR CELL RESEARCH

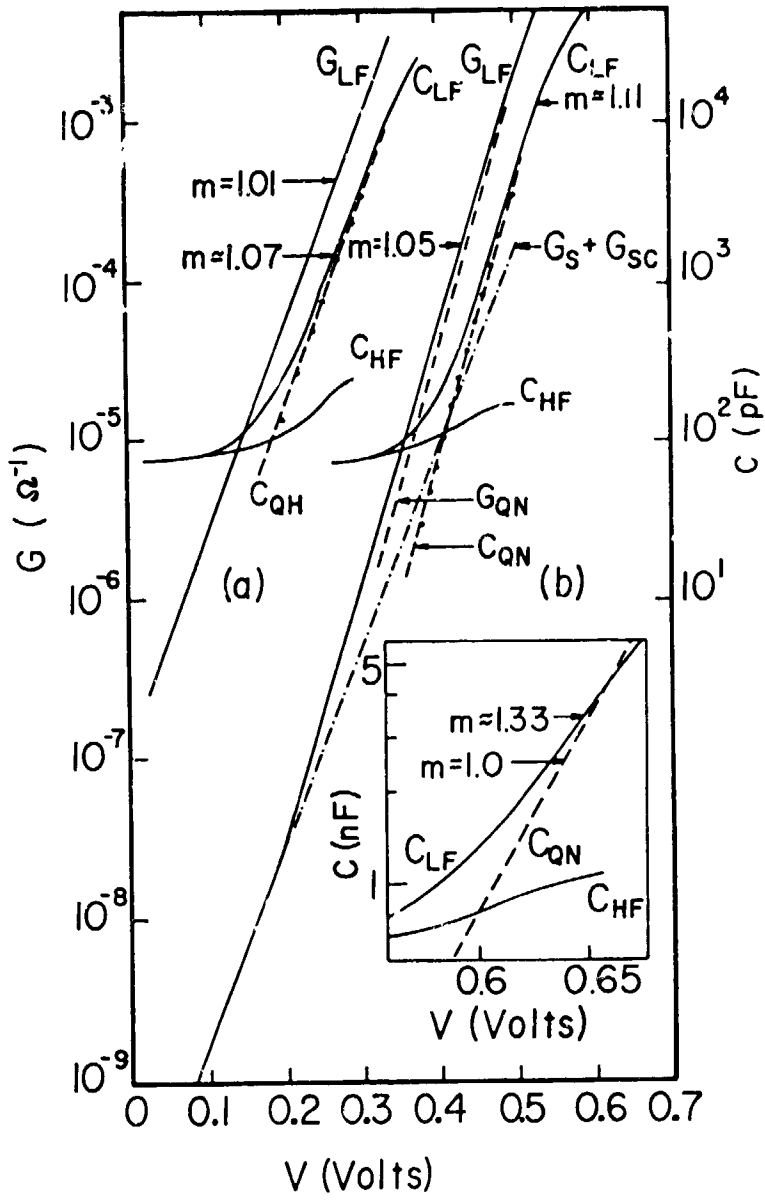


(a)

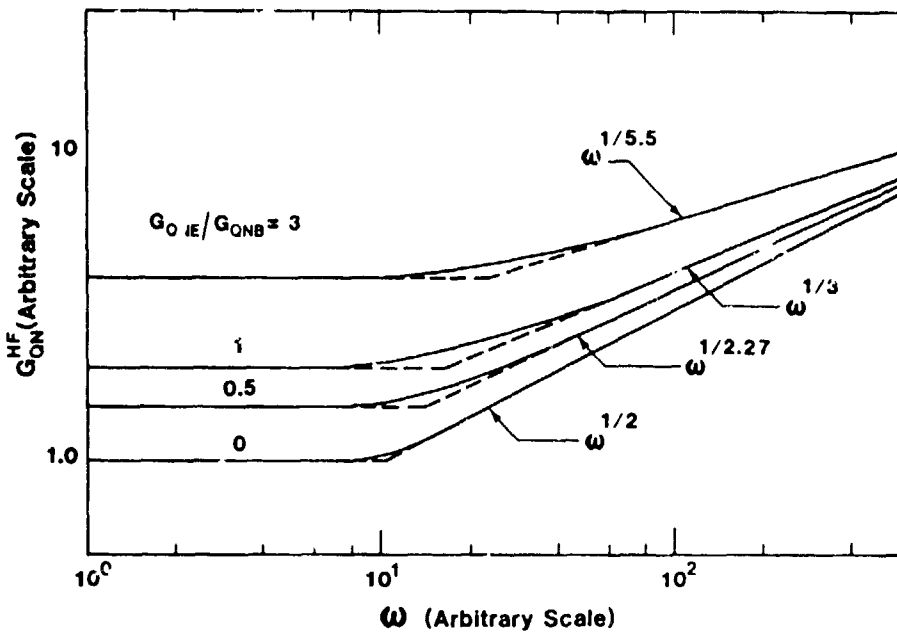


(b)

HIGH-EFFICIENCY SILICON SOLAR CELL RESEARCH



HIGH-EFFICIENCY SILICON SOLAR CELL RESEARCH



Recommendations

- 1. USE ~~NEW~~ ^{OLD-RENEWED} ENERGY GAP MODEL IN COMPUTER SIMULATION. ΔE_G
 - 2. USE ESSCD + $Y(j\omega, V)$ FOR τ_B AND S_{BSF}
- NEAR TERM EFFORTS:
- 1. NEW EXPERIMENTS TO EXPLORE ENERGY GAP MODEL FURTHER. ΔE_G
 - 2. ADAPT S_E AND τ_E MEASUREMENTS TO EMITTER, USING $Y(j\omega)$.
 - 3. THEORY TO ACCOUNT FOR ΔE_D & ΔE_A IMPURITY BAND INFLUENCE FOR MODERATELY HIGH DENSITIES: 10^{18}
 - 4. ACCOUNT FOR HOLES AND AND ELECTRONS IN SCR TO IMPROVE ACCURACY OF OPEN-CIRCUIT VOLTAGE DECAY C_{SCR} G_{SCR}
- 1. $\Delta E_G, \oplus \Delta E_D + \Delta E_A$
 - 2. $S_{BSF}, \tau_B, \oplus S_E, \tau_E$